



#### N-CHANNEL ENHANCEMENT MODE MOSFET

### **Product Summary**

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> max	I <sub>D</sub> max T <sub>A</sub> = +25°C	
30V	20mΩ @ V <sub>GS</sub> = 10V	7.2A	
	31mΩ @ V <sub>GS</sub> = 4.5V	5.8A	

### **Description**

This MOSFET has been designed to minimize the on-state resistance ( $R_{DS(ON)}$ ) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

### **Applications**

- Backlighting
- Power Management Functions
- DC-DC Converters

### **Features and Benefits**

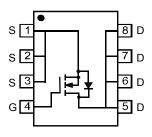
- Low On-Resistance
- Low Input Capacitance
- Fast Switching Speed
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 standards for High Reliability

#### **Mechanical Data**

- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound.
   UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections Indicator: See diagram
- Terminals: Finish Matte Tin annealed over Copper leadframe.
   Solderable per MIL-STD-202, Method 208 (3)
- Weight: 0.008 grams (approximate)



Top View



Top View Internal Schematic

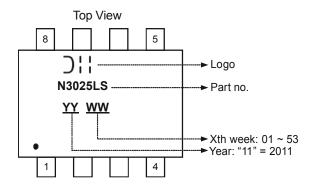
### Ordering Information (Note 4)

Part Number	Case	Packaging
DMN3025LSS-13	SO-8	2500/Tape & Reel

Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.
- 2. See http://www.diodes.com for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at http://www.diodes.com.

## Marking Information





## **Maximum Ratings** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic			Symbol	Value	Units	
Drain-Source Voltage			$V_{\mathrm{DSS}}$	30	V	
Gate-Source Voltage			V <sub>GSS</sub>	±20	V	
Continuous Prain Current (Note 6) // - 10/	Steady State	T <sub>A</sub> = +25°C T <sub>A</sub> = +70°C	I <sub>D</sub>	7.2 5.7	Α	
Continuous Drain Current (Note 6) V <sub>GS</sub> = 10V	t<10s	T <sub>A</sub> = +25°C T <sub>A</sub> = +70°C	I <sub>D</sub>	9.6 7.7	А	
Maximum Continuous Body Diode Forward Current (Note 6)			I <sub>S</sub>	3	Α	
Pulsed Drain Current (10µs pulse, duty cycle = 1%)			I <sub>DM</sub>	40	Α	
Avalanche Current (L = 0.1mH)			I <sub>AS</sub>	14.5	Α	
Repetitive Avalanche Energy (L = 0.1mH)			E <sub>AS</sub>	10.5	mJ	

# Thermal Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Units		
Total Power Dissipation (Note 5)	T <sub>A</sub> = +25°C	Б	1.4	W	
Total Fower Dissipation (Note 5)	T <sub>A</sub> = +70°C	$P_{D}$	0.9	VV	
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	R <sub>0,JA</sub>	87	°C/W	
Thermal Resistance, Junction to Ambient (Note 3)	t<10s	МөЈА	44	C/VV	
Total Power Dissipation (Note 6)	$T_A = +25^{\circ}C$	D-	1.7	W	
Total Fower Dissipation (Note 0)	T <sub>A</sub> = +70°C	$P_{D}$	1.1	VV	
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	R <sub>0,JA</sub>	73	°C/W	
Thermal Resistance, Junction to Ambient (Note 0)	t<10s	NejA	37	C/VV	
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C		

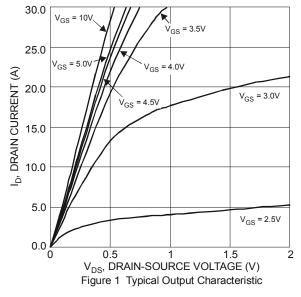
## **Electrical Characteristics** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

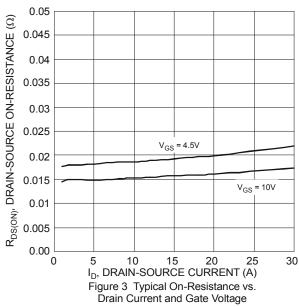
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 7)							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	30	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	_	1	μΑ	$V_{DS} = 30V, V_{GS} = 0V$	
Gate-Source Leakage	I <sub>GSS</sub>	_	_	±1	μΑ	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 7)	*	•	•	•	•		
Gate Threshold Voltage	V <sub>GS(th)</sub>	8.0	-	2.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
Static Drain-Source On-Resistance	_		14	20	mΩ	$V_{GS} = 10V, I_D = 10A$	
Static Drain-Source On-Resistance	R <sub>DS (ON)</sub>	_	23	31		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 7.5A	
Forward Transfer Admittance	Y <sub>fs</sub>	_	11	-	S	$V_{DS} = 5V, I_{D} = 10A$	
Diode Forward Voltage	V <sub>SD</sub>	_	0.70	1.0	V	$V_{GS} = 0V, I_{S} = 1A$	
DYNAMIC CHARACTERISTICS (Note 8)				-			
Input Capacitance	C <sub>iss</sub>	_	641			V <sub>DS</sub> = 15V, V <sub>GS</sub> = 0V, f = 1.0MHz	
Output Capacitance	Coss	_	66	_	pF		
Reverse Transfer Capacitance	C <sub>rss</sub>	_	50	_		1 = 1:000112	
Gate resistance	Rg	_	2.2	_	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$	
Total Gate Charge (V <sub>GS</sub> = 4.5V)	Qg	_	6	_			
Total Gate Charge (V <sub>GS</sub> = 10V)	Qq	_	13.2	_		V <sub>DS</sub> = 15V, I <sub>D</sub> = 10A	
Gate-Source Charge	Qgs	_	1.7	_	nC		
Gate-Drain Charge	Q <sub>gd</sub>	_	2.2	_			
Turn-On Delay Time	t <sub>D(on)</sub>	_	3.3	_			
Turn-On Rise Time	t <sub>r</sub>	_	4.4	_		$V_{DD} = 15V, V_{GS} = 10V,$ $R_{G} = 6\Omega, I_{D} = 1A$	
Turn-Off Delay Time	t <sub>D(off)</sub>	_	22.3	_	ns		
Turn-Off Fall Time	t <sub>f</sub>	_	5.3	_			

5. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout. 6. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate. Notes:

7. Short duration pulse test used to minimize self-heating effect. 8. Guaranteed by design. Not subject to product testing.







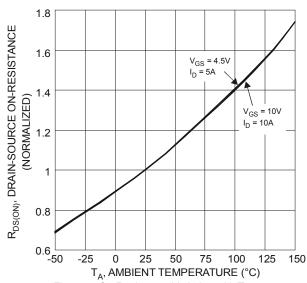
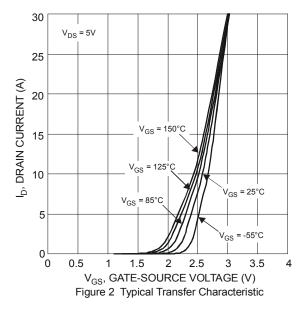
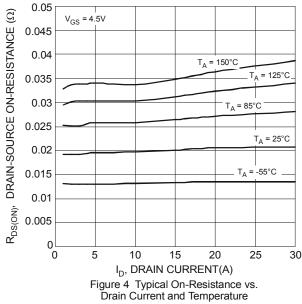


Figure 5 On-Resistance Variation with Temperature





0.04 DRAIN-SOURCE ON-RESISTANCE (Ω) 0.035 V<sub>GS</sub> = 4.5V 0.03 I<sub>D</sub> = 5A 0.025  $V_{GS} = 10V$ 0.02 I<sub>D</sub> = 10A 0.015 0.01 R<sub>DS(ON)</sub>, 0.005 0 -50 -25 0 25 50 75 100 125

T<sub>A</sub>, AMBIENT TEMPERATURE (°C)
Figure 6 On-Resistance Variation with Temperature



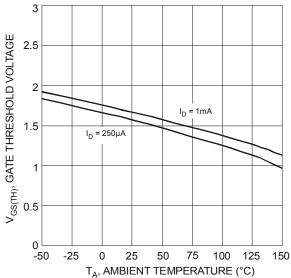


Figure 7 Gate Threshold Variation vs. Ambient Temperature

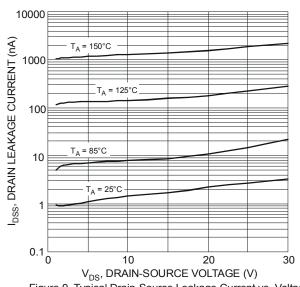


Figure 9 Typical Drain-Source Leakage Current vs. Voltage

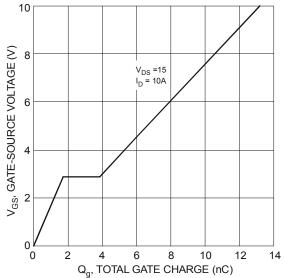
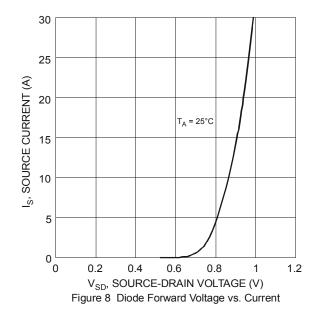
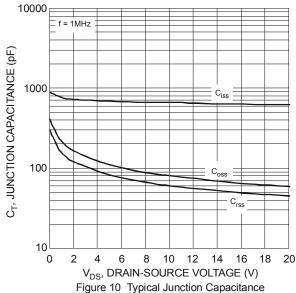
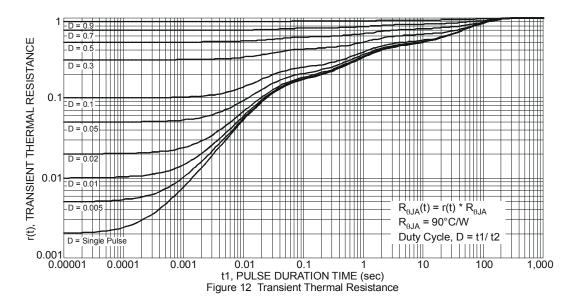


Figure 11 Gate-Source Voltage vs. Total Gate Charge

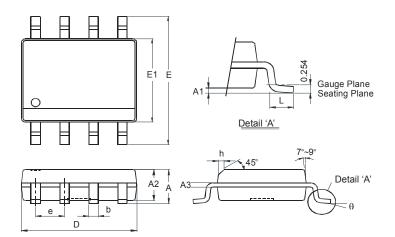






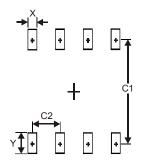


## **Package Outline Dimensions**



SO-8				
Dim	Min	Max		
Α	ı	1.75		
A1	0.10	0.20		
A2	1.30	1.50		
A3	0.15	0.25		
b	0.3	0.5		
D	4.85	4.95		
E	5.90	6.10		
E1	3.85	3.95		
е	1.27 Typ			
h	-	0.35		
L	0.62	0.82		
θ	0°	8°		
All Dimensions in mm				

## Suggested Pad Layout



Dimensions	Value (in mm)
X	0.60
Y	1.55
C1	5.4
C2	1.27



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